Advance Information

Single-Channel Transient Voltage Suppressor

Product Description

The CM6114 is an Application Specific Integrated Passive™ (ASIP[™]) component in a 2 x 2, 4-bump, 0.4 mm pitch, CSP form factor. This device is designed for:

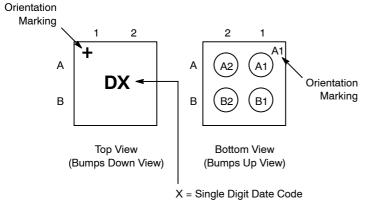
- Fuse
- Transient Voltage Suppression (TVS)
- Electrostatic Discharge Protection
- Electrical Overstress Protection

- 4-Bump, 0.8 mm X 0.8 mm Footprint Chip Scale Package (CSP)
- These Devices are Pb-Free and are RoHS Compliant

Table 1. PIN DESCRIPTIONS

4-bump CSP Package		
Pin Description		
A1	Fuse Terminal 1	
A2	TVS Channel / Fuse Terminal 2	
B1 and B2	Device Ground	

PACKAGE / PINOUT DIAGRAMS



4-Bump CSP Package



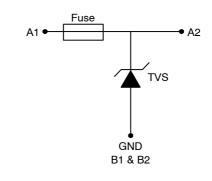
ON Semiconductor®

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CASE 567CB

ELECTRICAL SCHEMATIC



MARKING DIAGRAM



D = CM6114

Х = Single Digit Date Code

ORDERING INFORMATION

Device	Package	Shipping [†]
CM6114	WLCSP4 (Pb-Free)	10,000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

This document contains information on a new product. Specifications and information herein are subject to change without notice.

ELECTRICAL SPECIFICATIONS AND CONDITIONS

Table 2. PARAMETERS AND OPERATING CONDITIONS

Parameter	Rating	Units
Storage Temperature Range	−55 to +150	°C
Operating Temperature Range	-30 to +85	°C

Table 3. ABSOLUTE RATINGS

Parameter	Rating	Units
Failing to nonconductive, I^2t – from A1 pin to device ground (Maximum I_{PP} value using 10/1000 μs pulse). See Notes 1 and 2.	4	Α
Failing to nonconductive, I ² t – from A2 pin to device ground (Maximum I _{PP} value using 10/1000 μs pulse). See Notes 1 and 2.	100	Α

^{1.} The device must not burn to open-circuit, when the value is below maximum IPP.

Table 4. ELECTRICAL OPERATING CHARACTERISTICS (Note 1)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
R	Resistance A1 – A2	B1 and B2 floating; T _A = 25°C (Note 2)			50	mΩ
R _{OPEN}	Resistance after open fuse	B1 and B2 floating; T _A = 25°C	1			MΩ
t _{FUSE}	Fusing time	B1 and B2 floating; I = 5 A; T _A = 25°C (Note 3)			100	ms
t _{LIFE}	Fuse life time	B1 and B2 floating; I = 2 A; T _A = 25°C (Notes 3 and 4)	4000			Hours
I _{OFF}	Stand-off quiescent current	From A1 pin to B1 and B2 pins; Stand-off voltage V _{OFF} = 8 V; T _A = 25°C			100	nA
V _{BR}	Break down voltage	From A1 pin to B1 and B2 pins; Break down current I _{BR} = 15 mA	10			V
V _{CL}	Clamping voltage during transient	From A1 pin to B1 and B2 pins; Clamping current I _{CL} = 1 A (Note 5)			13.5	V
V _F	Forward voltage	From A1 pin to B1 and B2 pins; Forward current I _F = 850 mA			1.3	V
C _{L1}	Line capacitance	V _{BIAS} = 0 V		280		pF
C _{L2}		V _{BIAS} = 5 V; T _A = 25°C	108	135		pF
V _{ESD}	ESD protection peak discharge Voltage at A1 pin or A2 to B1 and B2 a) Contact Discharge per IEC 61000-4-2 standard b) Air Discharge per IEC 61000-4-2 standard	T _A = 25°C (Note 6)	±30 ±30			kV
f _C	Minimum attenuation Freq = 80 MHz - 1 GHz Freq = 1 - 4 GHz	$R_{SOURCE} = R_{LOAD} = 50 \Omega$ $T_A = 25$ °C		12 20		dB

^{2.} This parameter is characterized at 25°C using an ON Semiconductor-specific test board.

All parameters specified for T_A = -30°C to 85°C unless otherwise noted.
 This parameter is measured using low current to avoid self-heating.
 These parameters are characterized using ON Semiconductor-specific test boards.

^{4.} Fuse is considered failed when its resistance is higher than 1 Ω . 5. Transient: 8 x 20 μ s current pulse.

^{6.} Standard IEC 61000–4–2 with $C_{Discharge}$ = 150 pF, $R_{Discharge}$ = 330 Ω .

RF CHARACTERISTICS

$T_A = 25$ °C, 50 Ω Environment

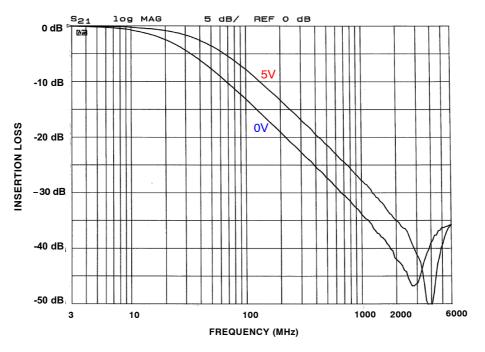


Figure 1. Insertion Loss (0 V and 5 V Bias)

MECHANICAL SPECIFICATION

Table 5. VERTICAL STRUCTURE DIMENSIONS (nominal)

Ref.	Parameter	Material	Dimension
а	Die Thickness	Silicon	389 μm
h	Dielectric Layer 1	Polyimide	7 μm
j	Dielectric Layer 2	Polyimide	10 μm
	UBM-(Ti/Cu)	Plated Cu	6.5 μm
d		Sputtered Cu	0.4 μm
		Sputtered Ti	0.1 μm
е	UBM Wetting Area Diameter		240 μm
b	Bump Standoff		194 μm
f	Solder Bump Diameter after Bump Reflow		270 μm
С	Metal Pad Height	AlSiCu	1.5 μm
g	Metal Pad Diameter		60 μm
D2			0.406 mm
D1	Total Thickness		0.600 mm

Vertical Structure Specification*

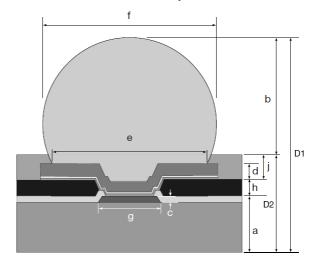
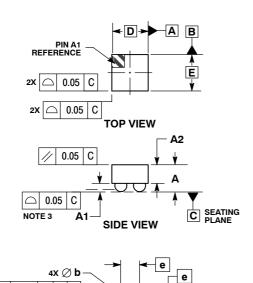


Figure 2. Sectional View

^{*} Daisy Chain CM6040

PACKAGE DIMENSIONS

WLCSP4, 0.8x0.8 CASE 567CB-01 **ISSUE 0**



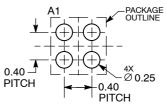
BOTTOM VIEW

NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
- CONTROLLING DIMENSION: MILLIMETERS. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS.

	MILLIMETERS				
DIM	MIN	MAX			
Α	0.57	0.63			
A1	0.17	0.24			
A2	0.41 REF				
b	0.24	0.29			
D	0.80 BSC				
E	0.80 BSC				
е	0.40 BSC				

RECOMMENDED **SOLDERING FOOTPRINT***



DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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